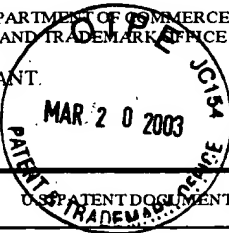


Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-1358		SERIAL NO. 09/643,004	
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*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
T.D	AA	4,913,090	04/1990	Harada et al		
	AB	6,307,184	10/2001	Womack et al		
	AC	5,616,208	04/1997	Lee		
	AD	6,203,618	03/2001	McMillan		
	AE	5,462,603	10/1995	Murakami		
	AF	6,399,921	06/2002	Johnsgard et al		
	AG	5,997,588	12/1999	Goodwin et al		
	AH	3,785,853	01/1974	Kirkman et al		
T.D	AI	6,139,695	10/2000	Washburn et al		
	AJ					

FOREIGN PATENT DOCUMENTS							
Document Number	Date	Country	Class	Subclass	Translation		
					Yes	No	
AK							
AL							
AM							
AN							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
T.D	AO		Aarik, et al, "Control of Thin Film Structure by Reactant Pressure in Atomic Layer Deposition of TiO <sub>2</sub> ," Journal of Crystal Growth, 169 (1996) pgs. 496-502
	AP		
	AQ		
	AR		

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U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
T.D	AA	2002/0125516	09/2002 Marsh et al				
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
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	AN						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AO						
	AP						
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	AR						
EXAMINER		T. DANG 4/4/03					
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